



12A, 600V N-CHANNEL MOSFET

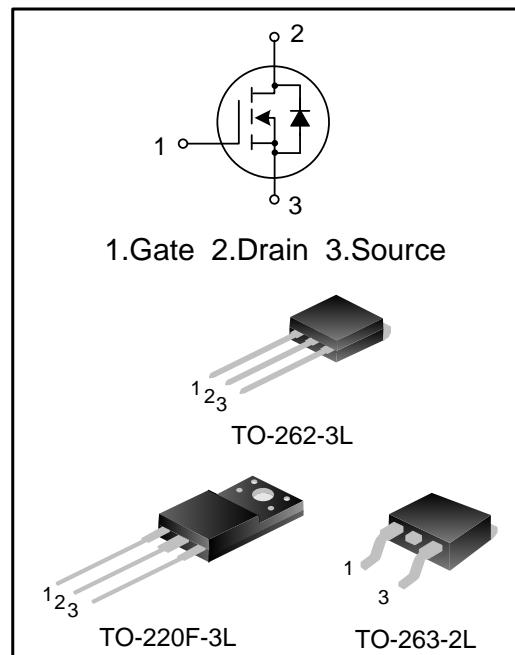
GENERAL DESCRIPTION

SVF12N60F/S/K is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ structure VDMOS technology. The improved process and cell structure have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are widely used in AC-DC power supplies, DC-DC converters and H-bridge PWM motor drivers.

FEATURES

- 12A,600V, $R_{DS(on)(typ.)}=0.58\Omega @ V_{GS}=10V$
- Low gate charge
- Low Crss
- Fast switching
- Improved dv/dt capability



ORDERING INFORMATION

Part No.	Package	Marking	Hazardous Substance Control	Packing Type
SVF12N60F	TO-220F-3L	SVF12N60F	Pb free	Tube
SVF12N60S	TO-263-2L	SVF12N60S	Halogen free	Tube
SVF12N60STR	TO-263-2L	SVF12N60S	Halogen free	Tape&Reel
SVF12N60K	TO-262-3L	SVF12N60K	Pb free	Tube



ABSOLUTE MAXIMUM RATINGS (T_c=25°C UNLESS OTHERWISE NOTED)

Characteristics	Symbol	Ratings			Unit
		SVF12N60F	SVF12N60S	SVF12N60K	
Drain-Source Voltage	V _{DS}	600			V
Gate-Source Voltage	V _{GS}	±30			V
Drain Current	T _c =25°C	I _D	12		A
	T _c =100°C		7.6		
Drain Current Pulsed	I _{DM}	48			A
Power Dissipation(T _c =25°C) -Derate above 25°C	P _D	51	180	213	W
		0.41	1.44	1.7	W/°C
Single Pulsed Avalanche Energy (Note 1)	E _{AS}	798			mJ
Reverse Diode dv/dt (Note 2)	dv/dt	4.5			V/ns
MOSFET dv/dt Ruggedness (Note 3)	dv/dt	50			V/ns
Operation Junction Temperature Range	T _J	-55~+150			°C
Storage Temperature Range	T _{stg}	-55~+150			°C

THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings			Unit
		SVF12N60F	SVF12N60S	SVF12N60K	
Thermal Resistance, Junction-to-Case	R _{θJC}	2.44	0.69	0.59	°C/W
Thermal Resistance, Junction-to-Ambient	R _{θJA}	62.5	62.5	62.5	°C/W

ELECTRICAL CHARACTERISTICS ($T_c=25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	600	--	--	V
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}}=600\text{V}, V_{\text{GS}}=0\text{V}$	--	--	1.0	μA
Gate-Source Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm30\text{V}, V_{\text{DS}}=0\text{V}$	--	--	±100	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}}=V_{\text{DS}}, I_{\text{D}}=250\mu\text{A}$	2.0	--	4.0	V
Static Drain- Source On State Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=6.0\text{A}$	--	0.58	0.75	Ω
Input Capacitance	C_g	$f=1.0\text{MHz}$	--	4.2	--	Ω
Input Capacitance	C_{iss}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1.0\text{MHz}$	--	1367	--	pF
Output Capacitance	C_{oss}		--	152	--	
Reverse Transfer Capacitance	C_{rss}		--	14	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=300\text{V}, I_{\text{D}}=12\text{A}, V_{\text{GS}}=10\text{V}, R_{\text{G}}=24\Omega$ (Note 4,5)	--	24	--	ns
Turn-on Rise Time	t_r		--	52	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	88	--	
Turn-off Fall Time	t_f		--	48	--	
Total Gate Charge	Q_g	$V_{\text{DS}}=480\text{V}, I_{\text{D}}=12\text{A}, V_{\text{GS}}=10\text{V}$ (Note 4,5)	--	34	--	nC
Gate-Source Charge	Q_{gs}		--	7.6	--	
Gate-Drain Charge	Q_{gd}		--	15	--	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

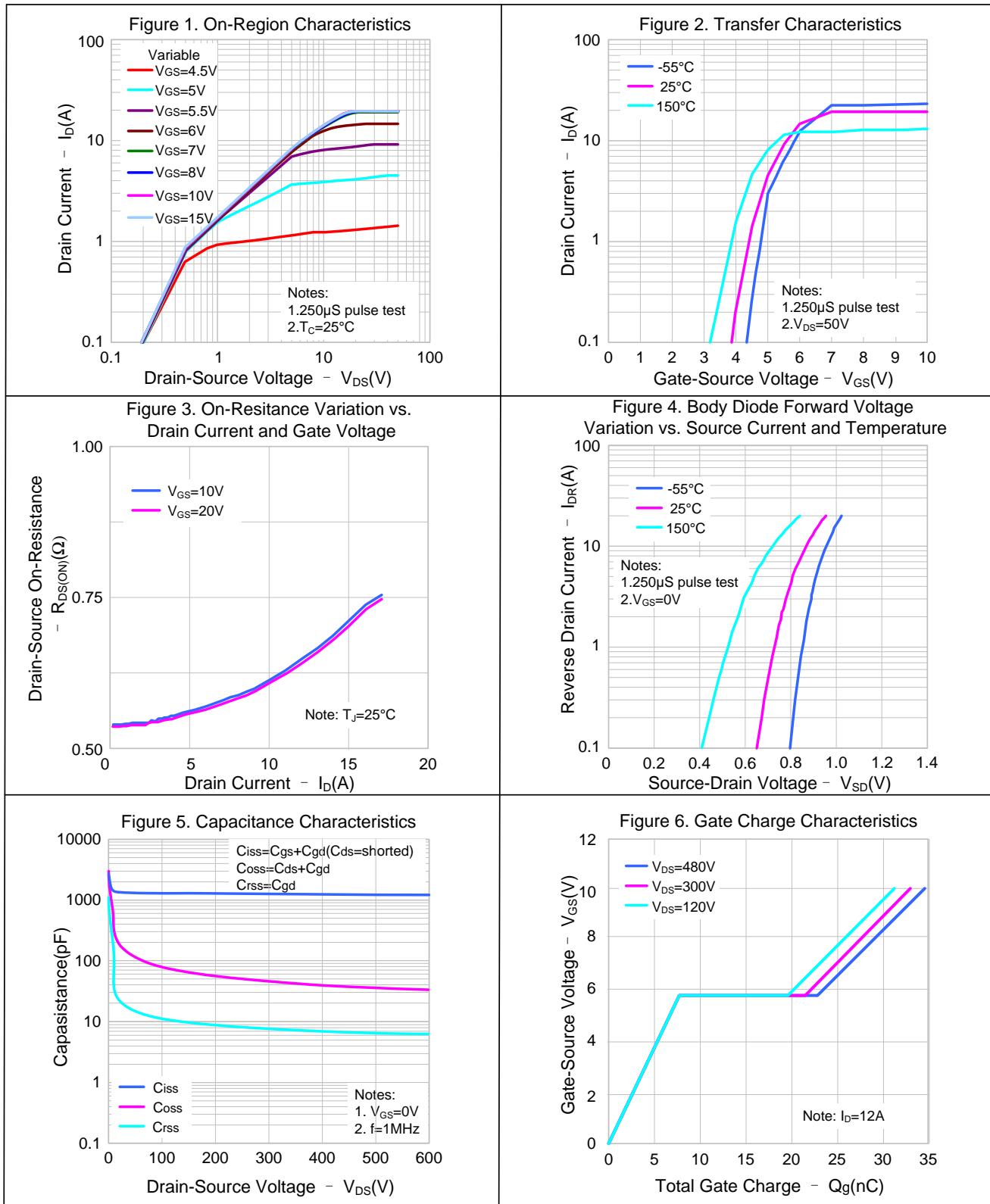
Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_s	Integral Reverse p-n Junction Diode in the MOSFET	--	--	12	A
Pulsed Source Current	I_{SM}		--	--	48	
Diode Forward Voltage	V_{SD}	$I_s=12\text{A}, V_{\text{GS}}=0\text{V}$	--	--	1.3	V
Reverse Recovery Time	T_{rr}	$I_s=12\text{A}, V_{\text{GS}}=0\text{V},$ $dI_F/dt=100\text{A}/\mu\text{s}$	--	530	--	ns
Reverse Recovery Charge	Q_{rr}		--	4.8	--	μC

Notes:

1. $L=30\text{Mh}, I_{\text{AS}}=6.7\text{A}, V_{\text{DD}}=100\text{V}, R_{\text{G}}=25\Omega$, starting temperature $T_J=25^\circ\text{C}$;
2. $V_{\text{DS}}=0\sim400\text{V}, I_{\text{SD}}\leq12\text{A}, T_J=25^\circ\text{C}$;
3. $V_{\text{DS}}=0\sim480\text{V}$;
4. Pulse Test: Pulse width $\leq300\mu\text{s}$, Duty cycle $\leq2\%$;
5. Essentially independent of operating temperature.



TYPICAL CHARACTERISTICS





TYPICAL CHARACTERISTICS(CONTINUED)

Figure 7. Breakdown Voltage Variation vs. Temperature

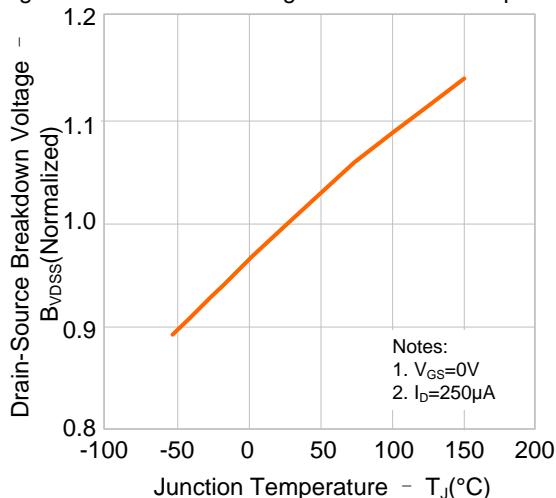


Figure 8. On-resistance Variation vs. Temperature

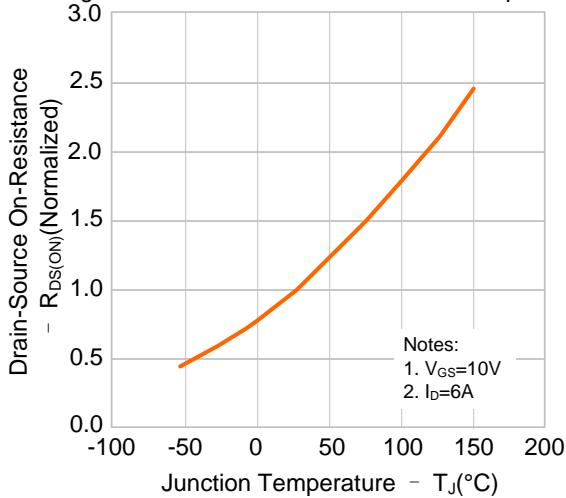


Figure 9-1. Max. Safe Operating Area(SVF12N60F)

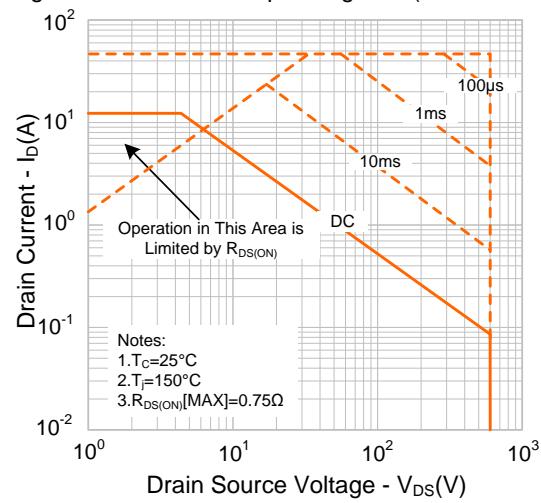


Figure 9-2. Max. Safe Operating Area(SVF12N60S)

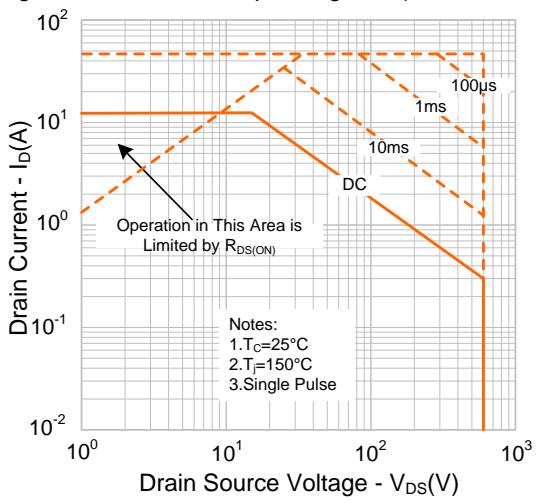


Figure 9-3. Max. Safe Operating Area(SVF12N60K)

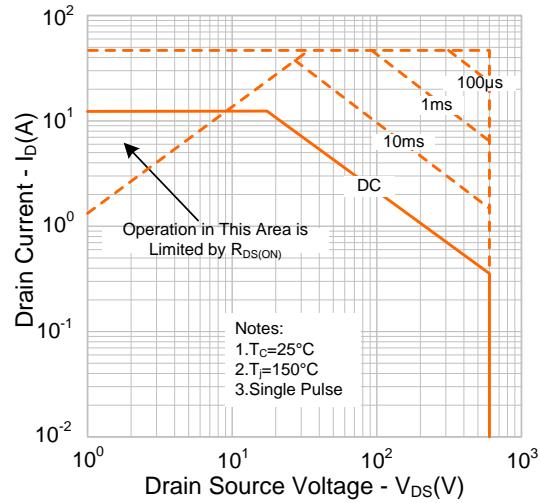
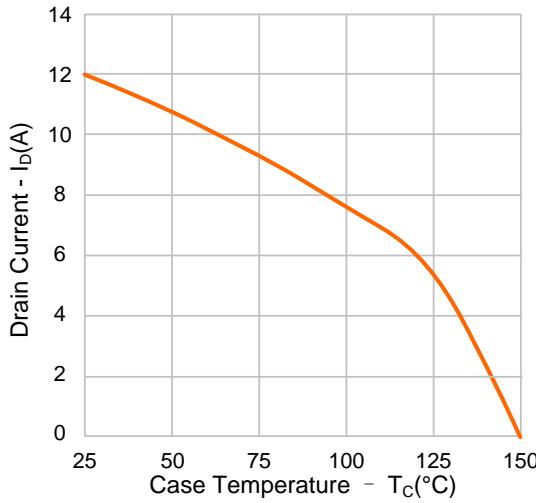
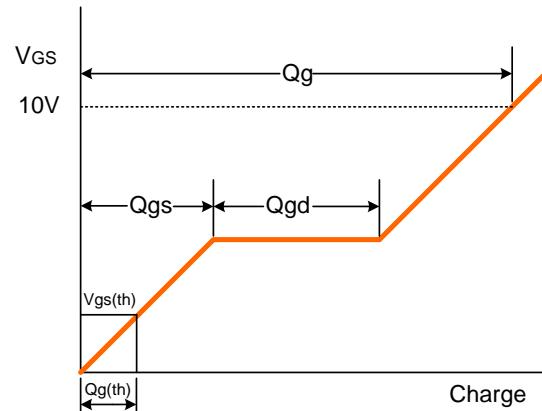
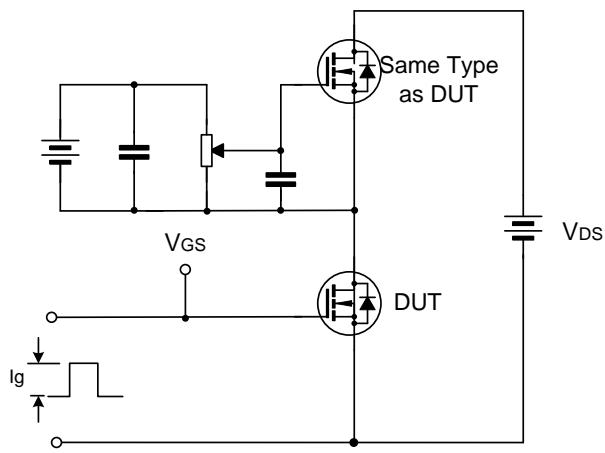


Figure 10. Maximum Drain Current vs. Case Temperature

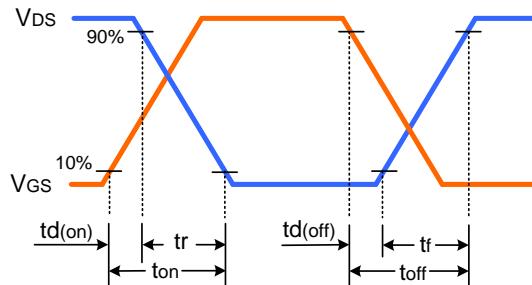
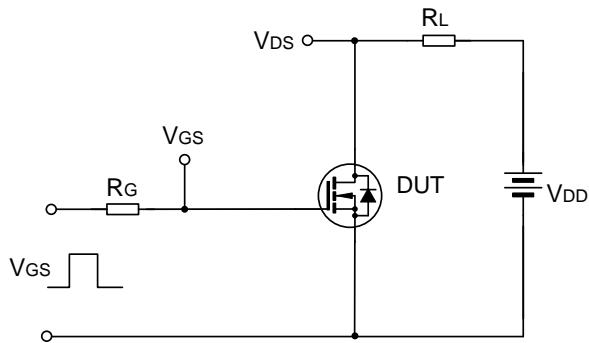


TYPICAL TEST CIRCUIT

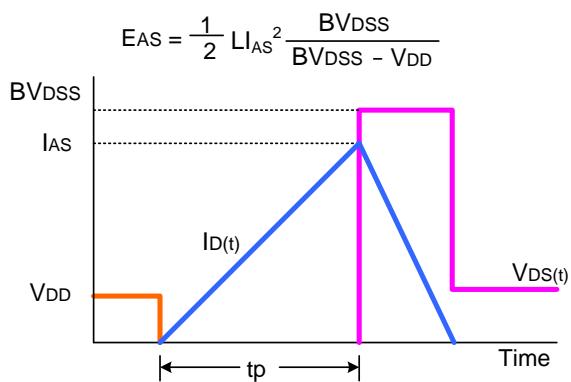
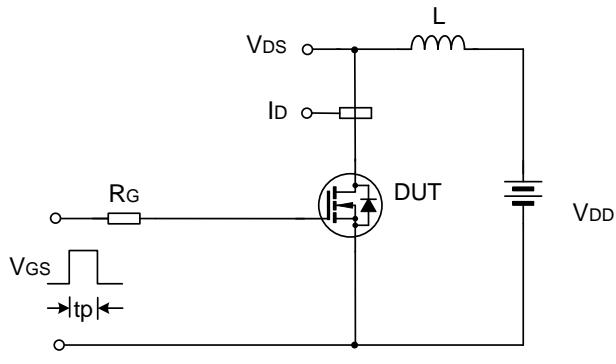
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform



Unclamped Inductive Switching Test Circuit & Waveform

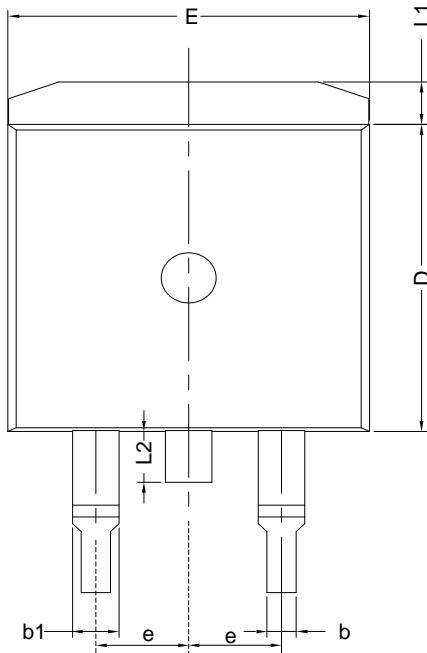




PACKAGE OUTLINE

TO-263-2L

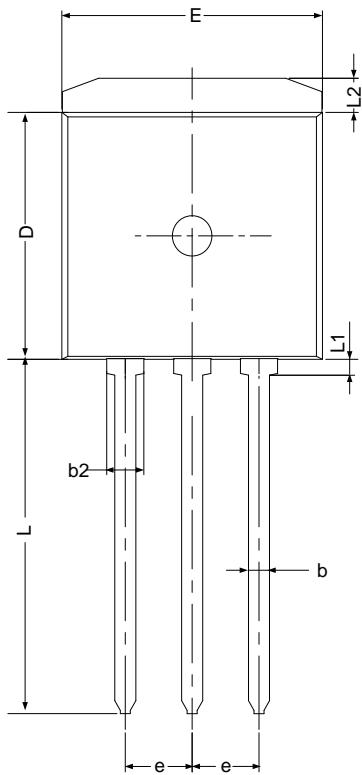
UNIT: mm



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	4.30	4.57	4.72
A1	0	0.10	0.25
b	0.71	0.81	0.91
c	0.30	—	0.60
c2	1.17	1.27	1.37
D	8.50	—	9.35
E	9.80	—	10.45
e	2.54BSC		
H	14.70	—	15.75
L	2.00	2.30	2.74
L1	1.12	1.27	1.42
L2	—	—	1.75

TO-262-3L

UNIT: mm

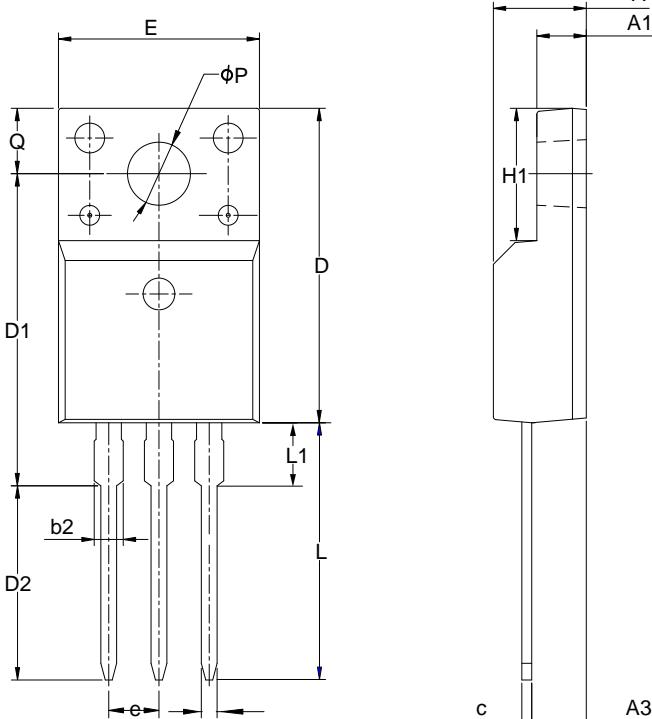


SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	4.30	4.50	4.70
A1	2.20	—	2.92
b	0.71	0.80	0.90
b2	1.20	—	1.50
c	0.34	—	0.65
c2	1.22	1.30	1.35
D	8.38	—	9.30
E	9.80	10.16	10.54
e	2.54 BSC		
L	12.80	—	14.10
L1	—	—	0.75
L2	1.12	—	1.42



PACKAGE OUTLINE(CONTINUED)

TO-220F-3L		UNIT: mm		
SYMBOL	MILLIMETER			
	MIN	NOM	MAX	
A	4.42	4.70	5.02	
A1	2.30	2.54	2.80	
A3	2.50	2.76	3.10	
b	0.70	0.80	0.90	
b2	—	—	1.47	
c	0.35	0.50	0.65	
D	15.25	15.87	16.25	
D1	15.30	15.75	16.30	
D2	9.30	9.80	10.30	
E	9.73	10.16	10.36	
e	2.54BSC			
H1	6.40	6.68	7.00	
L	12.48	12.98	13.48	
L1	—	—	3.50	
φP	3.00	3.18	3.40	
Q	3.05	3.30	3.55	



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- The instructions are subject to change without notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
- Our products are consumer electronic products, and / or civil electronic products.
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- Product promotion is endless, our company will wholeheartedly provide customers with better products!
- Website: <http://www.silan.com.cn>

Part No.: **SVF12N60F/S/K**

Document Type: **Datasheet**

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Rev.: **2.7**

Revision History:

1. Update Electrical schematic and Typical Test circuit
 2. Delete NOMENCLATURE
 3. Update the template of the datasheet
-

Rev.: **2.6**

Revision History:

1. Update Fig 5
 2. Add dv/dt and Rg
-

Rev.: **2.5**

Revision History:

1. Update the package outline of TO-262-3L
-

Rev.: **2.4**

Revision History:

1. Delete the package outline of TO-220-3L
-

Rev.: **2.3**

Revision History:

1. Add another solid figure of TO-220-3L
 2. Update the package outline of TO-262-3L and TO-263-2L
-

Rev.: **2.2**

Revision History:

1. Modify the Electrical characteristics
-

Rev.: **2.1**

Revision History:

1. Modify the ordering information
 2. Modify the package information of TO-220-3L
-

Rev.: **2.0**



Revision History:

1. Modify the package information

Rev.: 1.9

Revision History:

1. Modify the thermal characteristics

Rev.: 1.8

Revision History:

1. Modify the ordering information

Rev.: 1.7

Revision History:

1. Change the schematic diagram of MOS

Rev.: 1.6

Revision History:

1. Modify "PACKAGE OUTLINE"

Rev.: 1.5

Revision History:

1. Add the package of TO-262-3L

Rev.: 1.4

Revision History:

1. Modify the typ. value of $R_{DS(on)}$

Rev.: 1.3

Revision History:

1. Modify the value of T_{rr} and Q_{rr}
2. Modify the value of capacitance
3. Modify the figure 5

Rev.: 1.2

Revision History:

1. Add the halogen free information of SVF12N60F

Rev.: 1.1

Revision History:

1. Modify "PACKAGE OUTLINE"

Rev.: 1.0

Revision History:

1. Original